

INTERNATIONAL STANDARD

**Printed electronics –
Part 402-1: Printability – Measurement of qualities – Line pattern widths**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

PRINTED ELECTRONICS –

**Part 402-1: Printability – Measurement of qualities –
Line pattern width**

FOREWORD

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This second edition cancels and replaces the first edition published in 2017. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) The title is changed from 'Printability – Measurement of qualities – Pattern width' to 'Printability – Measurement of qualities – Line pattern width'
- b) The term 'pattern width' is specified as 'line pattern width'.
- c) The measurement method of line pattern space is included.